Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO252 (DPAK) surface mountable plastic package intended for use in applications requiring high bidirectional blocking voltage, High surge current capability and high thermal cycling performance.

2. Features and benefits

- · High bidirectional blocking voltage capability
- High surge current capability
- · High thermal cycling performance
- Surface mountable package

3. Applications

- Ignition circuits
- Motor control
- · Protection circuits
- Voltage regulation

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{RRM}	repetitive peak reverse voltage		-	-	500	V
$I_{T(AV)}$	average on-state current	half sine wave; T _{mb} ≤ 103 °C; <u>Fig. 1</u>	-	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 103 ^{\circ}\text{C}$; Fig. 2; Fig. 3	-	-	12	Α
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5	-	-	120	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	-	-	132	Α
Tj	junction temperature		-	-	125	°C
Static chara	acteristics					
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 8</u>	-	2	15	mA
Dynamic ch	naracteristics		,	'		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; Fig. 13	200	1000	-	V/µs

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		V_{DM} = 335 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	50	130	-	V/µs

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	L mp	A - [
2	Α	anode		G sym037
3	G	gate		Symosi
mb	A	mounting base; connected to anode		
			DPAK (TO252N)	

6. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
BT151S-500R	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	TO252N		

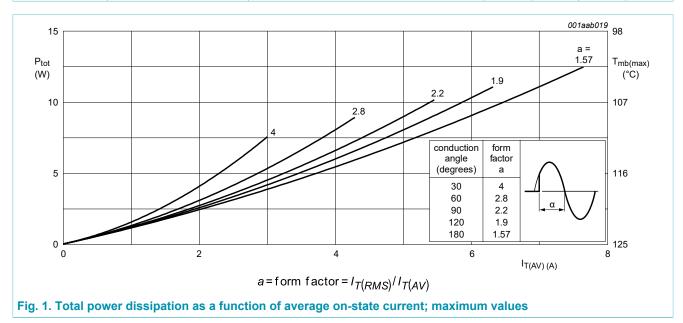
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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	500	V
V_{RRM}	repetitive peak reverse voltage		-	500	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 103 °C; <u>Fig. 1</u>	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; T _{mb} ≤ 103 °C; <u>Fig. 2;</u> <u>Fig. 3</u>	-	12	A
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5	-	120	Α
		half sine wave; T _{j(init)} = 25 °C; t _p = 8.3 ms	-	132	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	72	A²s
dl _T /dt	rate of rise of on-state current	I _G = 30 mA	-	50	A/µs
I _{GM}	peak gate current		-	2	Α
V_{RGM}	peak reverse gate voltage		-	5	V
P_{GM}	peak gate power		-	5	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.5	W
T _{stg}	storage temperature		-40	150	°C
T _j	junction temperature		-	125	°C



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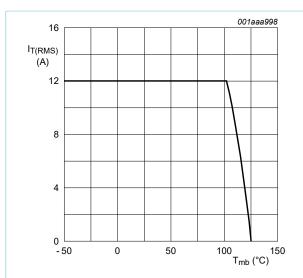


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values

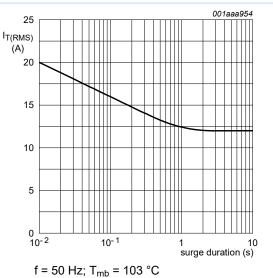


Fig. 3. RMS on-state current as a function of surge duration; maximum values

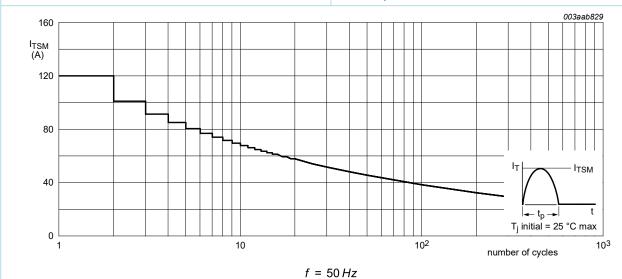
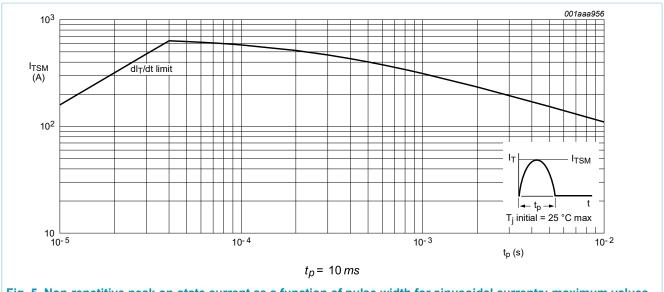


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	-	1.8	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	mounted on an FR4 printed-circuit board; Fig. 7	-	75	-	K/W

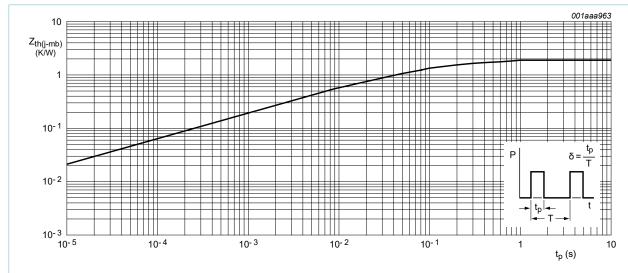


Fig. 6. Transient thermal impedance from junction to mounting base as as function of pulse width

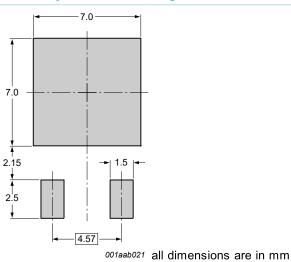


Fig. 7. Minimum footprint SOT428

9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 8$	-	2	15	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 9$	-	10	40	mA
l _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u>	-	7	20	mA
V_{T}	on-state voltage	I _T = 23 A; T _j = 25 °C; <u>Fig. 11</u>	-	1.4	1.75	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 12	-	0.6	1	V
		$V_D = 500 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C};$ Fig. 12	0.25	0.4	-	V
I _D	off-state current	V _D = 500 V; T _j = 125 °C	-	0.1	0.5	mA
I _R	reverse current	V _R = 500 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic ch	naracteristics			·		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; Fig. 13	200	1000	-	V/µs
		V_{DM} = 335 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	50	130	-	V/µs
t _{gt}	gate-controlled turn-on time	I_{TM} = 40 A; V_D = 500 V; I_G = 0.1 A; dI_G/dt = 5 A/µs; T_j = 25 °C	-	2	-	μs
t _q	commutated turn-off time	$V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; V_R = 25 \text{ V}; (dI_T/dt)_M = 30 \text{ A/µs}; dV_D/dt = 50 \text{ V/µs}; R_{GK(ext)} = 100 \Omega; (V_{DM} = 67\% \text{ of V}_{DRM})$	-	70	-	μs

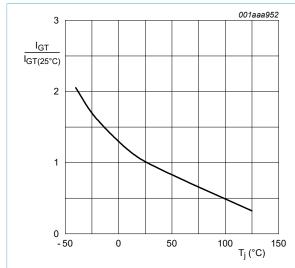


Fig. 8. Normalized gate trigger current as a function of junction temperature

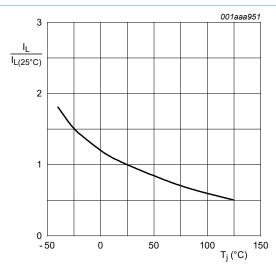


Fig. 9. Normalized latching current as a function of junction temperature

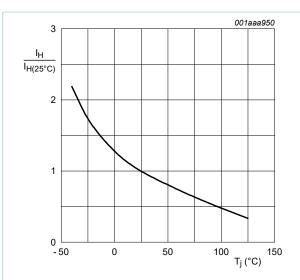
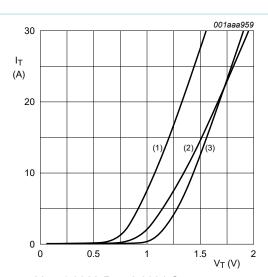


Fig. 10. Normalized holding current as a function of junction temperature



 V_o = 1.06 V; R_s = 0.0304 Ω (1) $T_j = 125$ °C; typical values (2) $T_j = 125$ °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 11. On-state current as a function of on-state voltage

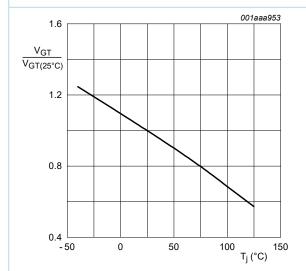
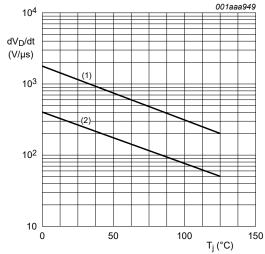


Fig. 12. Normalized gate trigger voltage as a function of junction temperature

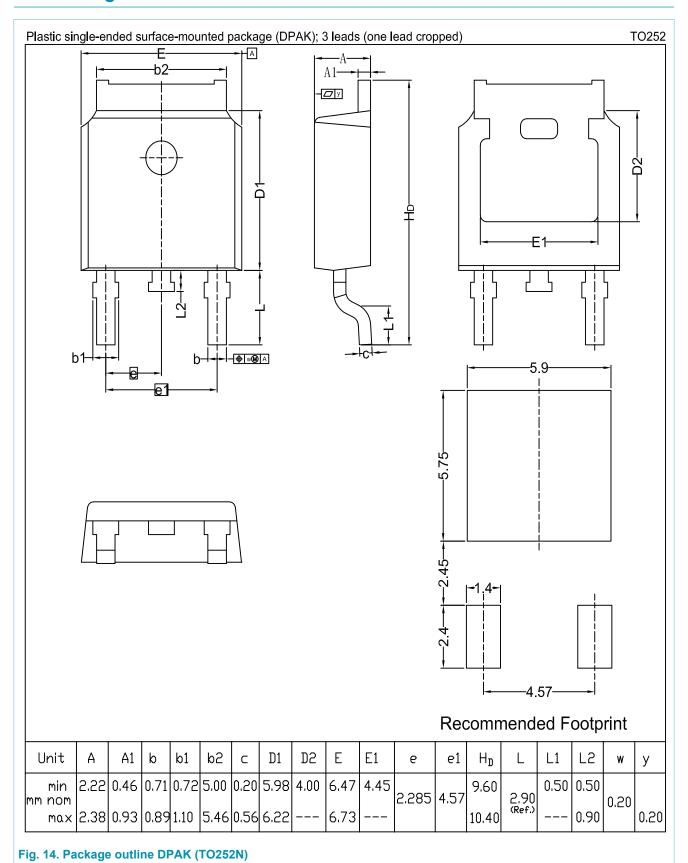


(1) $R_{GK} = 100 \Omega$; (2) gate open circuit

Fig. 13. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

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10. Package outline



11. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Date of release: 5 September 2018

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